

Optical Coating Characterization System Design and Qualification

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Abstract

The Space Dynamics Laboratory designed and built the optical coating characterization system (OCCS) cryogenic system for spectral (FTIR) measurement of optical transmittance and reflectance at temperatures of 90K and higher. The OCCS is designed to make cryogenic transmittance measurements from normal up to a 50 degree angle-of-incidence, and reflectance measurements between 40 and 50 degrees angle-of-incidence, in a converging optical beam of F/2 or greater. The system can measure up to 20, 1-inch diameter, optical components in a single cold cycle, or fewer larger components with flat surfaces up to 3 inches in diameter. This presentation will provide a brief overview of the OCCS design, followed by test results showing the performance achieved during qualification measurements.

Cold Testing

250

200

150

Cold Test #1 Temperature Data



Alignment & Focus







Focus Spots

Turn Vertical

On-Axis ±1

Investigate tolerance to FTS position alignment error



•Detector offset demonstrates detector centration on optical axis Detector focus demonstrates depth of focus (detector underfilled) •Predicted depth of focus: 6.2 mm •Measured depth of focus: ~6 mm Measurements indicate excellent margin for alignment and focus

Warm Testing with Si Camera FPA (2)

Investigate tolerance to detector alignment error



OCCS Design Goals & Optical Schematic



Warm Testing with Si Camera FPA (3)

Investigate tolerance to detector focus error

Focus Spots

Turn Horizontal

On-Axis ±1



Warm Testing with Si Camera FPA (4)

Investigate detector focus performance in reflection



•Large number of samples •Removable filter wheel plate to simplify sample exchange •Commercial OTS optics

OCCS Motion Functions

7 Motion Axes:

Axis Name	Туре	Range of Motion	Description
Filter Wheel Offset	Translation	± 1.5"	Filter horizontal position (moves filter test point, consistent with 3 inch sample size)
Filter Focus	Translation	± 0.5"	Filter location relative to focus point along optical axis
Detector Focus	Translation	± 0.5"	Detector and optics position along optical axis
Detector Offset	Translation	± 0.5"	Detector horizontal position relative to nominal optical axis
Detector Angle	Rotation	0° to 150°	Detector position relative to incoming optical axis
Filter Angle	Rotation	-15° to +55°	Filter angle relative to incident axis (sets test angle of incidence)
Filter Wheel Rotate	Rotation	± 180°	Filter test position (moves filter test point)

-2mm	-Imm	+1mm	+2mm

vs. Detector Focus

2mm Detector

Outline

Focus Spot

vs. FTS Table Angle

On-Axis

•Camera images indicate excellent optical performance margin •Apparent spot size on FPA confirms predicted focus spot (0.7 mm) •Small spot size on detector provides good resolution to find detector edges for alignment

•Detector remains underfilled over more than the adjustment range needed for alignment

Sapphire Spectra

Sapphire transmittance and reflectance measurements with Si camera FPA show good agreement with prediction



•Reflectance measurements require careful attention to capture reflections from sample front and back surfaces

CaF, Spectra Sapphire Spectra Sapphire transmittance from Pyroelectric detector Calcium Fluoride transmittance from Pyroelectric detector





OCCS Wavelength Calibration

•OCCS measured atmospheric spectral lines match prediction •Mean wavelength error: -0.017%



Silicon transmittance from Pyroelectric detector

Silicon Spectra

Transmittance vs Angle of Incidence

Bandpass filter transmittance versus angle of incidence



OCCS Photograph

•OCCS fits into existing SDL dewar •OCCS dewar mounts to optical bench with FTS and interface optics to form complete system



Optics

Assembly

•Mean uncertainty: 0.006%



Summary

•OCCS capability and performance has been demonstrated

- Measured transmittances match prediction
- •Angle-of-incidence capability demonstrated
- •Wavelength scale calibration matches expectation

•OCCS provides an efficient and reliable test capability for industry

- •SDL has extensive experience in cryogenic filter transmittance measurements
- •Installation of parts under test into OCCS is adaptable to a wide range of optical configurations
- •Large numbers of parts can be tested in one OCCS cold cycle

